Government Agencies Technology Exchange in Manufacturing (GATE-M)

INTERAGENCY PROGRAM REVIEW

at the National Institute of Standards and Technology (NIST)
Gaithersburg, Maryland¹

June 24-25, 2003

PURPOSE OF THIS REVIEW: To provide a forum for the federal agencies participating or interested in GATE-M to exchange program-level information about agency activities in the areas of Intelligence in Manufacturing and Nano-/Micro-Scale Systems and Technologies.

The review will result in the identification of opportunities for collaboration, coordination, and leverage among the agencies in these areas, as well as the identification of agency priorities and gaps in addressing them.

Tuesday, June 24

0.00	C 00 /	1 10 4
8:00	Coffee /	breakfast

8:30 Workshop Welcome

Dr. Arden Bement, Director, NIST

8:50 GATE-M Overview and Charge to the Participants

David Stieren, Strategic Relations Manager, NIST Manufacturing Engineering Laboratory (MEL) and GATE-M Panel Executive Secretary

9:10 Agency Overviews

9:10 Department of Commerce / NIST

Dr. Dale Hall, Director, NIST MEL, and GATE-M Panel Chair

9:30 Department of Defense (DOD)

Dan Cundiff, Associate Director, Manufacturing Technology and Affordability, Office of the Undersecretary of Defense for Advanced Systems and Concepts

9:50 Department of Energy (DOE)

National Nuclear Security Administration (NNSA)

Julianne Levings, Program Manager, Advanced Design and Production Technologies Campaign

¹ Room locations at NIST will be communicated prior to the event.

10:10		BREAK	
10:30		Resume Agency Overviews	
10:		DOE Office of Energy Efficiency and Renewable Energy (EERE) Harvey Wong, Manager, EERE Industrial Technologies	
10:5	Stational Aeronautics and Space Administration (NASA) John Vickers, Manager, National Center for Advanced Manufacturing, NASA Marshall Space Flight Center		
11:1	-	National Science Foundation (NSF) Dr. George Hazelrigg, Program Director, NSF Division of Design, Manufacture and Industrial Innovation	
11:30		Preview of Afternoon Sessions	
11:40		LUNCH	
12:45	ı	Technical Review Sessions	
	Session	I: Intelligence in Manufacturing	
12:45-2:00 2:05-3:20 3:25-4:40		20 NASA Programs	
	Session	II: Nano- / Micro-Scale Systems and Technologies	
	12:45-2 2:05-3: 3:25-4:	20 NASA Programs	
4:45		Day 1 Summary and Day 2 Preview	
5:00		ADJOURN	
Wedn	esday, J	une 25	
7:30		Coffee / breakfast	
8:00		Agenda Review / Plan for the Day	
8:15	ı	Technical Review Sessions	
	Session	III: Intelligence in Manufacturing	
	8:15-9: 9:35-10	0	

10:55-12:10 DOC / NIST Programs

Session IV: Nano-/Micro-Scale Systems and Technologies

8:15-9:30 DOE EERE Programs 9:35-10:50 DOD Programs 10:55-12:10 DOC / NIST Programs

12:15 LUNCH
 1:20 Introduction to Afternoon Sessions
 1:30 GATE-M Issue Working Sessions
 Group A: Intelligence in Manufacturing Group B: Nano- / Micro-Scale Systems and Technologies
 3:00 Working Group Reports
 3:30 Summary Discussion and Next Steps

ADJOURN

4:00